Explanatory Models for Understanding Differential Item Functioning

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Purpose

- Evaluate use of item-level features as explanatory variables for understanding DIF
- Understanding item-level features' impact could change the way we write items to avoid DIF

Methods

- Simulated data from 3-PL IRT model
 - 1,000 examinees taking 40-item test; Focal and reference groups: N=500
 - Reference group $\theta \sim N(0, 1)$; Focal group $\theta \sim N(-0.5, 1)$
 - Difficulty: *b* ~N(0, 1); Discrimination: *a* ~U(0.5, 3.5); Lower asymptote: *c* ~U(0.1, 0.3)
 - 2 items with DIF: $D \sim N(1, 0.1^2)$; 38 items w/ random, negligible DIF: $D \sim N(0, 0.1^2)$
 - Comparing 100 simulated datasets using:
 - Logistic regression followed by ordinary least squares regression (two-stage)
 - Fully Bayesian Hierarchical Generalized Linear Model (simultaneous)





Histogram of R^2 estimates from the linear regression of DIF estimates (two-stage) True $R^2 = 0.25$

Histogram of R^2 estimates from the Bayesian HGLM procedure True $R^2 = 0.25$

Density plots of DIF estimates for items simulated to have meaningful DIF.



• Bayesian HGLM is a reliable procedure for evaluating & interpreting DIF with respect to interpretable item features

• Bayesian HGLM was more precise and accurate in estimating DIF & relationship (i.e., R^2) between DIF & item features